

<b>Notice of References Cited</b>	Application/Control No. 10/581,959		Applicant(s)/Patent Under Reexamination YOON, IL SHIK	
	Examiner Stefan Kruer		Art Unit 3654	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,337,525	08-1994	Zaccai et al.	52/35
*	B	US-2003/0213199	11-2003	Bongio et al.	52/506.01
*	C	US-5,412,912	05-1995	Alves, Manuel J.	52/36.5
*	D	US-3,175,656	03-1965	SCHOENFELD ROBERT W	52/733.1
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 02013590 A	01-1990	Japan	NAKAJIMA, HIDEMOTO	B66B 11/02
	O	JP 05230928 A	09-1993	Japan	SHISHIDO et al.	E04B 9/14
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.